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#### DIFFERENTIAL-TO-LVDS/0.7V DIFFERENTIAL PCI EXPRESS™ JITTER ATTENUATOR

## ICS8741004

## **General Description**

HiPerClockS™

The ICS8741004 is a high performance Differential-to-LVDS/0.7V Differential Jitter Attenuator designed for use in PCI Express™ systems. In some PCI Express systems, such as those found in desktop PCs, the PCI Express clocks

are generated from a low bandwidth, high phase noise PLL frequency synthesizer. In these systems, a jitter attenuator may be required to attenuate high frequency random and deterministic jitter components from the PLL synthesizer and from the system board. The ICS8741004 has 3 PLL bandwidth modes: 200kHz, 600kHz and 2MHz. The 200kHz mode will provide maximum jitter attenuation, but with higher PLL tracking skew and spread spectrum modulation from the motherboard synthesizer may be attenuated. The 600kHz provides an intermediate bandwidth that can easily track triangular spread profiles, while providing good jitter attenuation. The 2MHz bandwidth provides the best tracking skew and will pass most spread profiles, but the jitter attenuation will not be as good as the lower bandwidth modes. Because some 2.5Gb serdes have x20 multipliers while others have x25 multipliers, the ICS8741004 can be set for 1:1 mode or 5/4 multiplication mode (i.e. 100MHz input/125MHz output) using the F SEL pins.

The ICS8741004 uses IDT's 3<sup>rd</sup> Generation FemtoClock<sup>™</sup> PLL technology to achieve the lowest possible phase noise. The device is packaged in a 24 Lead TSSOP package, making it ideal for use in space constrained applications such as PCI Express add-in cards.

#### **PLL Bandwidth**

BW\_SEL 0 = PLL Bandwidth: ~200kHz Float = PLL Bandwidth: ~600kHz (default) 1 = PLL Bandwidth: ~2MHz

## Features

- Two LVDS and two 0.7V differential output pairs Bank A has two LVDS output pairs and Bank B has two 0.7V differential output pairs
- One differential clock input pair
- CLK, CLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- Output frequency range: 98MHz 160MHz
- Input frequency range: 98MHz 128MHz
- VCO range: 490MHz 640MHz
- Cycle-to-cycle jitter: 35ps (maximum)
- Full 3.3V operating supply
- Three bandwidth modes allow the system designer to make jitter attenuation/tracking skew design trade-offs
- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

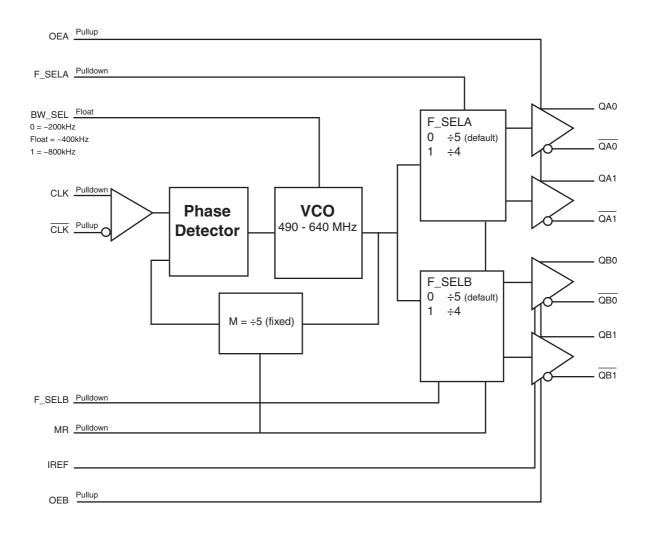
### **Pin Assignment**

QA1	1	24	QB1
QA1 🗆	2	23	QB1
Vddo 🗖	3	22	
QA0 🗆	4	21	QB0
	5	20	
MR 🗆	6	19	🗆 IREF
BW_SEL	7	18	F_SELB
nc 🗖	8	17	🗆 OEB
V <sub>DDA</sub>	9	16	GND
F_SELA	10	15	GND
V <sub>DD</sub>	11	14	
OEA 🗆	12	13	CLK

#### ICS8741004

24-Lead TSSOP 4.4mm x 7.8mm x 0.925mm package body G Package Top View

## **Block Diagram**



## Table 1. Pin Descriptions

Number	Name	Ţ	уре	Description
1, 24	QA1, QA1	Output		Differential output pair. LVDS interface levels.
3, 22	V <sub>DDO</sub>	Power		Output supply pins.
4, 5	QA0, <u>QA0</u>	Output		Differential output pair. LVDS interface levels.
6	MR	Input	Pulldown	Active High Master Reset. When logic HIGH, the internal dividers are reset causing the true outputs Q[Ax:Bx] to go LOW and the inverted outputs $\overline{Q[Ax:Bx]}$ to go HIGH. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS/LVTTL interface levels.
7	BW_SEL	Input	Pullup/ Pulldown	PLL Bandwidth input. LVCMOS/LVTTL interface levels. See Table 3B.
8	nc	Unused		No connect.
9	V <sub>DDA</sub>	Power		Analog supply pin.
10	F_SELA	Input	Pulldown	Frequency select pins for QAx/QAx outputs. LVCMOS/LVTTL interface levels. See Table 3C.
11	V <sub>DD</sub>	Power		Core supply pin.
12	OEA	Input	Pullup	Output enable for QAx pins. When HIGH, QAx/ $\overline{QAx}$ outputs are enabled. When LOW, the QAx/ $\overline{QAx}$ outputs are in a high impedance state. LVCMOS/LVTTL interface levels. See Table 3A.
13	CLK	Input	Pulldown	Non-inverting differential clock input.
14	CLK	Input	Pullup	Inverting differential clock input.
15, 16	GND	Power		Power supply ground.
17	OEB	Input	Pullup	Output enable for QBx pins. When HIGH, QBx/QBx outputs are enabled. When LOW, the QBx/QBx outputs are in a high impedance state. LVCMOS/LVTTL interface levels. See Table 3A.
18	F_SELB	Input	Pulldown	Frequency select pins for QBx/QBx outputs. LVCMOS/LVTTL interface levels. See Table 3C.
19	IREF	Input		A fixed precision resistor (RREF = $475\Omega$ ) from this pin to ground provides a reference current used for differential current-mode QB0/nQB0 clock outputs.
20, 21	<u>QB0</u> , QB0	Output		Differential output pair. HCSL interface levels.
23, 24	QB1, QB1	Output		Differential output pair. HCSL interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

## **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ

## **Function Tables**

Table 3A. Output Enable Function Table

Inp	outs	Outputs			
OEA	OEB	QA[0:1]/QA[0:1]	QB[0:1]/QB[0:1]		
0	0	Hi-Z	Hi-Z		
1	1	Enabled	Enabled		

#### Table 3B. PLL Bandwidth Function Table

Input	
BW_SEL	PLL Bandwidth
0	~200kHz
Float	~600kHz (default)
1	~2MHz

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>DD</sub>	4.6V
Inputs, V <sub>I</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, V <sub>O</sub>	-0.5V to V <sub>DDO</sub> + 0.5V
Package Thermal Impedance, $\theta_{JA}$	82.3°C/W (0 mps)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

## **DC Electrical Characteristics**

#### Table 4A. Power Supply DC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ , $T_A = 0^{\circ}C$ to $70^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>DD</sub>	Positive Supply Voltage		3.135	3.3	3.465	V
V <sub>DDA</sub>	Analog Supply Voltage		V <sub>DD</sub> – 0.12	3.3	V <sub>DD</sub>	V
V <sub>DDO</sub>	Output Supply Voltage		3.135	3.3	3.465	V
I <sub>DD</sub>	Power Supply Current				45	mA
I <sub>DDA</sub>	Analog Supply Current				12	mA
I <sub>DDO</sub>	Output Supply Current				80	mA

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
VIH	Input High Voltage	OEA, OEB, MR, F_SELA, F_SELB		2		V <sub>DD</sub> + 0.3	V
		BW_SEL		V <sub>DD</sub> – 0.3		V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage	OEA, OEB, MR, F_SELA, F_SELB		-0.3		0.8	V
	BW_SEL		-0.3		+0.3	V	
V <sub>IM</sub>	Input Mid Voltage	BW_SEL		V <sub>DD</sub> /2 - 0.1		V <sub>DD</sub> /2 + 0.1	V
IIH	Input High Current	F_SELA, F_SELB, MR, BW_SEL	V <sub>DD</sub> = V <sub>IN</sub> = 3.465V			150	μA
		OEA, OEB	$V_{DD} = V_{IN} = 3.465V$			5	μA
I <sub>IL</sub> Input Low (	Input Low Current	MR, F_SELA, F_SELB,	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-5			μA
		OEA, OEB, BW_SEL	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-150			μA

## Table 4B. LVCMOS/LVTTL DC Characteristics, V\_{DD} = V\_{DDO} = 3.3V ± 5%, T<sub>A</sub> = 0°C to 70°C

#### Table 4C. Differential DC Characteristics, $V_{\text{DD}}$ = $V_{\text{DDO}}$ = 3.3V ± 5%, $T_{\text{A}}$ = 0°C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	Input High Current	CLK	$V_{DD} = V_{IN} = 3.465V$			150	μA
I <sub>IH</sub> Input High Current	CLK	$V_{DD} = V_{IN} = 3.465V$			5	μA	
I <sub>IL</sub> Input Low Current	CLK	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-5			μA	
		CLK	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-150			μA
V <sub>PP</sub>	Peak-to-Peak Voltage			0.15		1.3	V
V <sub>CMR</sub>	Common Mode Input Voltage; NOTE 1			GND + 0.5		V <sub>DD</sub> - 0.85	V

NOTE 1: Common mode input voltage is defined as  $V_{IH}$ .

#### Table 4D. LVDS DC Characteristics, $V_{\text{DD}}$ = $V_{\text{DDO}}$ = 3.3V ± 5%, $T_{\text{A}}$ = 0°C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OD</sub>	Differential Output Voltage		290	390	490	mV
$\Delta V_{OD}$	V <sub>OD</sub> Magnitude Change				50	mV
V <sub>OS</sub>	Offset Voltage		1.2	1.35	1.5	V
$\Delta V_{OS}$	V <sub>OS</sub> Magnitude Change				50	mV

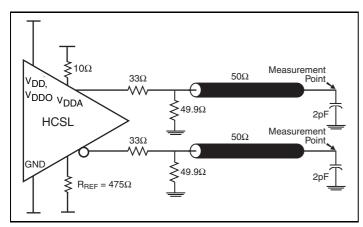
## **AC Electrical Characteristics**

#### Table 5. 0.7V Differential AC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ , $T_A = 0^{\circ}C$ to $70^{\circ}C$

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency			98		160	MHz
<i>t</i> jit(cc)	Cycle-to-Cycle Jitter; NOTE	1				35	ps
<i>t</i> sk(b)	Bank Skew, NOTE 2					30	ps
V <sub>HIGH</sub>	Output Voltage High	QBx/QBx		530		870	ps
V <sub>LOW</sub>	Output Voltage Low	QBx/QBx		-150			ps
V <sub>OVS</sub>	Max. Voltage, Overshoot	QBx/QBx				V <sub>HIGH</sub> + 0.35	V
V <sub>UDS</sub>	Min. Voltage, Undershoot	QBx/QBx		-0.3			V
V <sub>rb</sub>	Ringback Voltage	QBx/QBx				0.2	V
V <sub>CROSS</sub>	Absolute Crossing Voltage	QBx/QBx	@ 0.7V Swing	250		550	mV
$\Delta V_{CROSS}$	Total Variation of V <sub>CROSS</sub> over all edges	QBx/QBx	@ 0.7V Swing			140	mV
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	QBx/QBx	measured between 0.175V to 0.525V	175		700	ps
		QAx/QAx	20% to 80%	250		600	ps
$\Delta t_{\sf R}$ / $\Delta t_{\sf F}$	Rise/Fall Time Variation	QBx/QBx				125	ps
t <sub>RFM</sub>	Rise/Fall Matching	QBx/QBx				20	%
odc	Output Duty Cycle	1		48		52	%

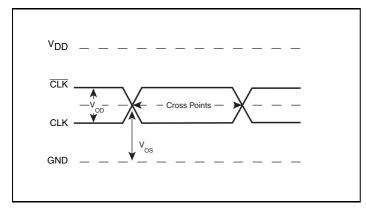
NOTE 1: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 2: Defined as skew within a bank of outputs at the same voltage and with equal load conditions.

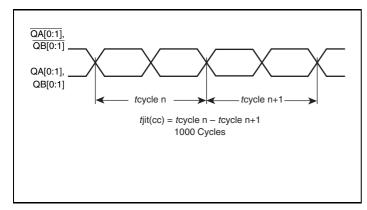


## Parameter Measurement Information

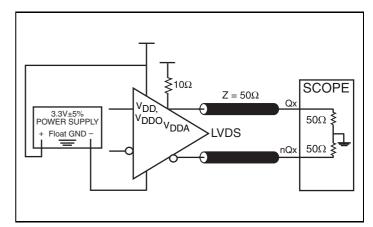
3.3V HCSL Output Load AC Test Circuit



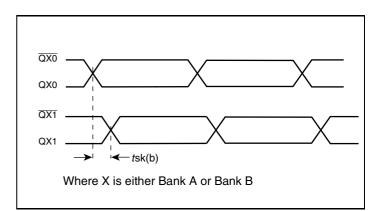
**Differential Input Level** 



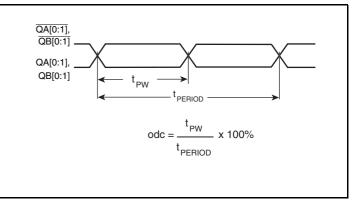
Cycle-to-Cycle Jitter



3.3V LVDS Output Load AC Test Circuit

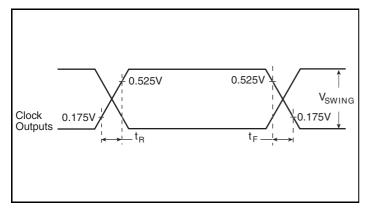




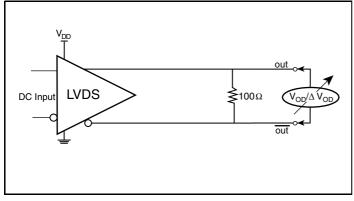


**Output Duty Cycle/Pulse Width/Period** 

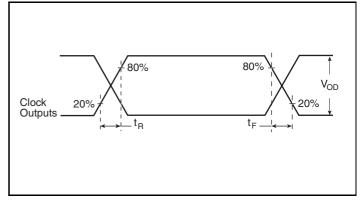
## Parameter Measurement Information, continued



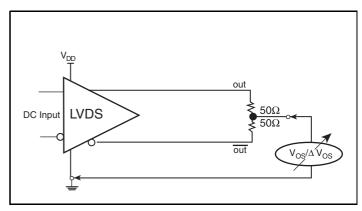
**HCSL Output Rise/Fall Time** 



**Differential Output Voltage Setup** 



LVDS Output Rise/Fall Time



**Offset Voltage Setup** 

## **Application Information**

#### **Power Supply Filtering Technique**

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. The ICS8741004 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL.  $V_{DD,}$   $V_{DDA}$  and  $V_{DDO}$  should be individually connected to the power supply plane through vias, and bypass capacitors should be used for each pin. To achieve optimum jitter performance, power supply isolation is required. *Figure 1* illustrates how a  $10\Omega$  resistor along with a  $10\mu$ F and a  $0.01\mu$ F bypass capacitor should be connected to each  $V_{DDA}$  pin.

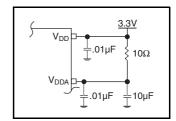


Figure 1. Power Supply Filtering

## Wiring the Differential Input to Accept Single Ended Levels

*Figure 2* shows how the differential input can be wired to accept single ended levels. The reference voltage V\_REF =  $V_{DD}/2$  is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of

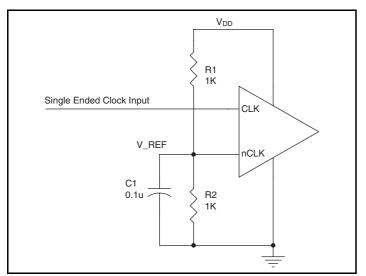


Figure 2. Single-Ended Signal Driving Differential Input

R1 and R2 might need to be adjusted to position the V\_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and  $V_{DD}$  = 3.3V, V\_REF should be 1.25V and R2/R1 = 0.609.

#### **Differential Clock Input Interface**

The CLK /CLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both signals must meet the V<sub>PP</sub> and V<sub>CMR</sub> input requirements. *Figures 3A to 3D* show interface examples for the HiPerClockS CLK/CLK input driven by the most common driver types. The input interfaces suggested here are

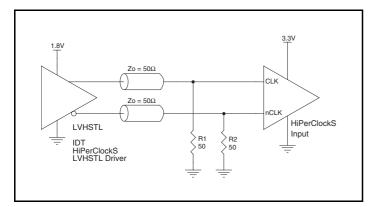


Figure 3A. HiPerClockS CLK/CLK Input Driven by an IDT HiPerClockS LVHSTL Driver

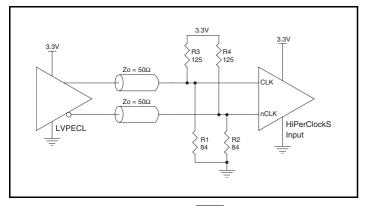


Figure 3C. HiPerClockS CLK/CLK Input Driven by a 3.3V LVPECL Driver

examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example, in Figure 3A, the input termination applies for IDT HiPerClockS LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

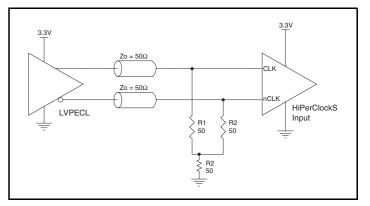


Figure 3B. HiPerClockS CLK/CLK Input Driven by a 3.3V LVPECL Driver

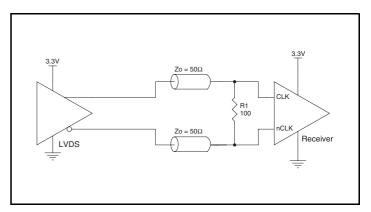


Figure 3D. HiPerClockS CLK/CLK Input Driven by a 3.3V LVDS Driver

#### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **LVCMOS Control Pins**

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **Outputs:**

#### **Differential Outputs**

All unused differential outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

#### **LVDS Outputs**

All unused LVDS output pairs can be either left floating or terminated with  $100\Omega$  across. If they are left floating, we recommend that there is no trace attached.

#### **LVDS Driver Termination**

A general LVDS interface is shown in *Figure 4*. In a 100 $\Omega$  differential transmission line environment, LVDS drivers require a matched load termination of 100 $\Omega$  across near the receiver input.

For a multiple LVDS outputs buffer, if only partial outputs are used, it is recommended to terminate the unused outputs.

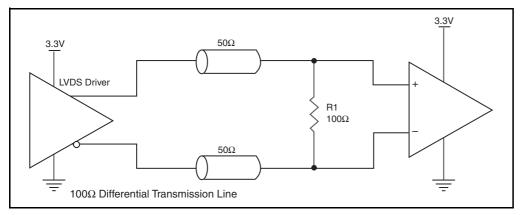


Figure 4. Typical LVDS Driver Termination

#### **Recommended Termination**

*Figure 5A* is the recommended termination for applications which require the receiver and driver to be on a separate PCB. All traces should be  $50\Omega$  impedance.

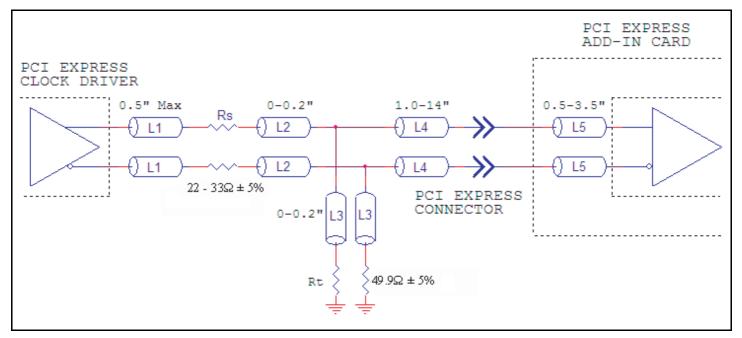


Figure 5A. Recommended Termination

*Figure 5B* is the recommended termination for applications which require a point to point connection and contain the driver and

receiver on the same PCB. All traces should all be 50  $\!\Omega$  impedance.

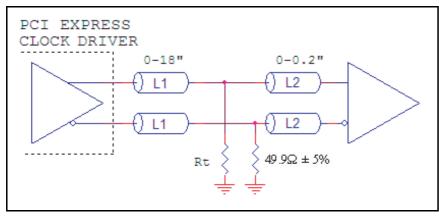


Figure 5B. Recommended Termination

## **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS8741004. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS741004 is the sum of the core power plus the **analog power** plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)<sub>MAX</sub> = V<sub>DD\_MAX</sub> \* (I<sub>DD\_MAX</sub> + I<sub>DDA\_MAX</sub>) = 3.465V \* (45mA + 12mA) = 197.5mW
- Power (LVDS\_output)<sub>MAX</sub> = V<sub>DDO\_MAX</sub> \* I<sub>DDO\_MAX</sub> = 3.465V \* 80mA = 227.2mW
- Power (HCSL\_output)<sub>MAX</sub> = 45.65mW \* 2 = 91.3mW

Total Power\_MAX = (3.465V, with all outputs switching) = 197.5mW + 277.2mW + 91.3mW = 556mW

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 82.3°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}C + 0.556W * 82.3^{\circ}C/W = 115.8^{\circ}C$ . This is below the limit of  $125^{\circ}C$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

#### Table 6. Thermal Resistance $\theta_{JA}$ for 24 Lead TSSOP, Forced Convection

$\theta_{JA}$ Vs. Air Flow					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	82.3°C/W	78.0°C/W	75.9°C/W		

#### 3. Calculations and Equations.

The purpose of this section is to calculate power dissipation on the IC per HCSL output pair. HCSL output driver circuit and termination are shown in *Figure 6.* 

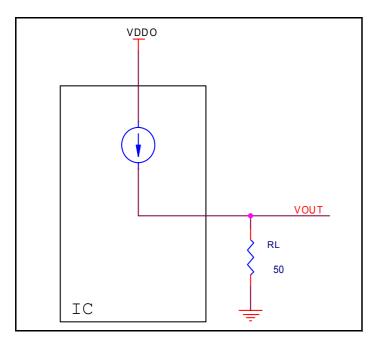


Figure 6. LVHSTL Driver Circuit and Termination

To calculate worst case power dissipation into the load, use the following equations which assume a  $50\Omega$  load and a termination voltage of V<sub>CCO</sub> – 2V.

Pd\_H is power dissipation when the output drives high.

Pd\_L is the power dissipation when the output drives low.

$$\begin{split} &\mathsf{Pd}\_\mathsf{H} = (\mathsf{V}_{\mathsf{OH}\_\mathsf{MAX}}/\mathsf{R}_\mathsf{L}) * (\mathsf{V}_{\mathsf{DD}\_\mathsf{MAX}} - \mathsf{V}_{\mathsf{OH}\_\mathsf{MAX}}) \\ &\mathsf{Pd}\_\mathsf{L} = (\mathsf{V}_{\mathsf{OL}\_\mathsf{MIN}}/\mathsf{R}_\mathsf{L}) * (\mathsf{V}_{\mathsf{DD}\_\mathsf{MAX}} - \mathsf{V}_{\mathsf{OL}\_\mathsf{MIN}}) \end{split}$$

$$\label{eq:Pd_H} \begin{split} \mathsf{Pd}_{-}\mathsf{H} &= (0.85 \mathsf{V} / 50 \Omega) * (3.465 \mathsf{V} - 0.87 \mathsf{V}) = \textbf{44.1mW} \\ \mathsf{Pd}_{-}\mathsf{L} &= (0.15 \mathsf{V} / 50 \Omega) * 0.15 \mathsf{V} = \textbf{0.45mW} \end{split}$$

Total Power Dissipation per output pair = Pd\_H + Pd\_L = 45mW

## **Reliability Information**

Table 7.  $\theta_{\text{JA}}$  vs. Air Flow Table for a 24 Lead TSSOP

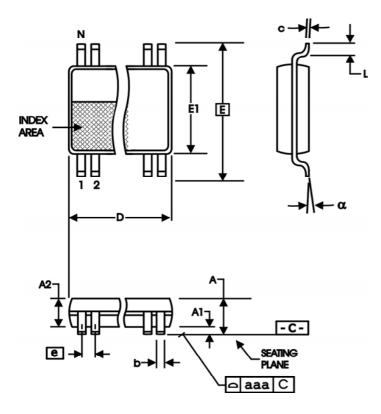
$\theta_{JA}$ vs. Air Flow					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	82.3°C/W	78.0°C/W	75.9°C/W		

#### **Transistor Count**

The transistor count for ICS8741004 is: 1318

## Package Outline and Package Dimension

#### Package Outline - G Suffix for 24 Lead TSSOP



#### Table 8. Package Dimensions

All Dimensions in Millimeters					
Symbol	Minimum Maximum				
Ν	24				
Α		1.20			
A1	0.5	0.15			
A2	0.80	1.05			
b	0.19	0.30			
С	0.09	0.20			
D	7.70	7.90			
E	6.40 Basic				
E1	4.30	4.50			
е	0.65 Basic				
L	0.45	0.75			
α	0°	8°			
aaa		0.10			

Reference Document: JEDEC Publication 95, MO-153

## **Ordering Information**

#### **Table 9. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8741004AG	ICS8741004AG	24 Lead TSSOP	Tray	0°C to 70°C
8741004AGT	ICS8741004AG	24 Lead TSSOP	2500 Tape & Reel	0°C to 70°C
8741004AGLF	ICS8741004AGLF	"Lead-Free" 24 Lead TSSOP	Tray	0°C to 70°C
8741004AGLFT	ICS8741004AGLF	"Lead-Free" 24 Lead TSSOP	2500 Tape & Reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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